

<b>Notice of References Cited</b>	Application/Control No. 10/774,308	Applicant(s)/Patent Under Reexamination VIEIRA ET AL.	
	Examiner Hanh Phan	Art Unit 2638	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,532,091	03-2003	Miyazaki et al.	398/175
*	C	US-2002/0075558	06-2002	Kim et al.	359/332
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**NON-PATENT DOCUMENTS**

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